What is claimed is:

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For: Calibration Artifact and Method of Using the Same

- 1 1. A calibration artifact for calibrating a machine vision measurement system,
- 2 the calibration artifact comprising:
- 3 a substrate; and
- a plurality of concentric rings on one surface of the substrate, each
- 5 ring of a different pre-defined size.
- 1 2. The calibration artifact of claim 1 wherein the change in the size of any two
- 2 adjacent rings is different than the change in size of any other two adjacent rings.
- 1 3. The calibration artifact of claim 1 in which each ring has an inner edge and
- 2 an outer edge.

MEC-118J KCT:nm

1	4.	A method of calibrating a machine vision measurement system, the method	
2	comprising:		
3		placing a calibration artifact including a series of concentric rings	
4	under a camera of the machine vision measurement system;		
5		choosing a magnification level;	
6		measuring the size of a first largest ring in pixels;	
7		measuring the size of a second largest ring in pixels;	
8		comparing the sizes; and	
9		determining, from the comparison, the actual diameter of said ring.	
1	5,	The method of claim 4 in which each ring is of a pre-determined different	
2	size and wherein the change in the size of any two adjacent rings is different than the		
3	change in size	e between any other two adjacent rings.	
1	6.	The method of claim 4 further including determining a first average of the	
2	measured size of the first largest ring in pixels and the measured size of the second largest		
3	ring in pixels.		
1	7.	The method of claim 6 further including measuring the size of a third largest	
2	ring in pixels	and determining a second average of the measured size of the third largest	
3	ring in pixels and the measured size of the second largest ring in pixels.		
1	8.	The method of claim 7 in which comparing includes using the first and	
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2 second averages.

1	9. A calibration artifact for a machine vision measurement system, the		
2	calibration artifact comprising:		
3	a substrate; and		
4	a plurality of concentric shapes on one surface of the substrate, each		
5	shape of a different pre-defined size and wherein the change between the size of any two		
6	adjacent shapes is different than the change in size between any other two adjacent shapes.		

l	10. A calibration system comprising:	
2	a calibration artifact including:	
3	a substrate; and	
4	a plurality of concentric rings on one surface of the substrate, each	
5	ring of a different pre-defined size and wherein the change between the size of any two	
5	adjacent rings is different than the change between the size of any other two adjacent rings;	
7	and	
8	a software algorithm including a database containing the size of each	
9	ring and data reflecting the change in size between each pair of adjacent rings	

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1	11.	A method of calibrating a machine vision measurement device, the method	
2	comprising:		
3		placing a calibration artifact including at least one ring with inner and	
4	outer edges under a camera of the machine measurement system;		
5		choosing a magnification level;	
6		measuring the size of the outer edge of the ring in pixels;	
7		measuring the size of the inner edge of the ring in pixels; and	
8		averaging the measured size of the outer edge of the ring and the inner	
9	edge of the ring.		